



## Short range biaxial strain relief mechanism within epitaxially grown BiFeO<sub>3</sub>

<sup>1</sup>State Univ. NY at Binghamton, <sup>2</sup>Lab. Mat. Struc. TIT,

<sup>3</sup>Grad. Sch. Eng. Tohoku Univ, <sup>5</sup>IMR Tohoku Univ., <sup>6</sup>CIES, <sup>7</sup>CSIS, <sup>8</sup>CSRN Tohoku Univ.

I.-T. Bae<sup>1</sup>, S. Yasui<sup>2</sup>, T. Ichinose<sup>3</sup>, M. Itoh<sup>2</sup>, T. Shiraishi<sup>4</sup>, T. Kiguchi<sup>4</sup>, °H. Naganuma<sup>3, 6-8</sup>

E-mail: tbae@binghamton.edu, hiroshi.naganuma.c3@tohoku.ac.jp

BiFeO<sub>3</sub> (BFO) epitaxial films change crystal symmetry on the various single crystal substrates.<sup>1)</sup> Although the growth mechanism depends on each substrate, there is not so many detail and systematic structural analysis using various angle of electron diffraction combined with X-ray diffraction. In this study, lattice mismatch-induced biaxial strain effect on the crystal structure and growth mechanism is investigated for the BFO films grown on La<sub>0.6</sub>Sr<sub>0.4</sub>MnO<sub>3</sub>/SrTiO<sub>3</sub> and YAlO<sub>3</sub> substrates. Nano-beam electron diffraction (NBED), structure factor calculation confirms that the crystal structure within both of the BFO thin films is rhombohedral by showing the rhombohedral signature Bragg's reflections. X-ray reciprocal space mapping (XRSM) unambiguously consistent with NBED. [Fig. 1] Further investigation with atomic resolution scanning transmission electron microscopy (STEM) reveals that while the ~1.0% of the lattice mismatch found in the BFO grown on La<sub>0.6</sub>Sr<sub>0.4</sub>MnO<sub>3</sub>/SrTiO<sub>3</sub> is exerted as biaxial in-plane compressive strain with atomistically coherent interface, [Fig. 1] the ~6.8% of the lattice mismatch found in the BFO grown on YAlO<sub>3</sub> is relaxed at the interface by introducing dislocations. The present result demonstrates the importance of: (1) identification of the epitaxial relationship between BFO and its substrate material to quantitatively evaluate the amount of the lattice strain within BFO film and (2) the atomistically coherent BFO/substrate interface for the lattice mismatch to exert the lattice strain.<sup>2)</sup>

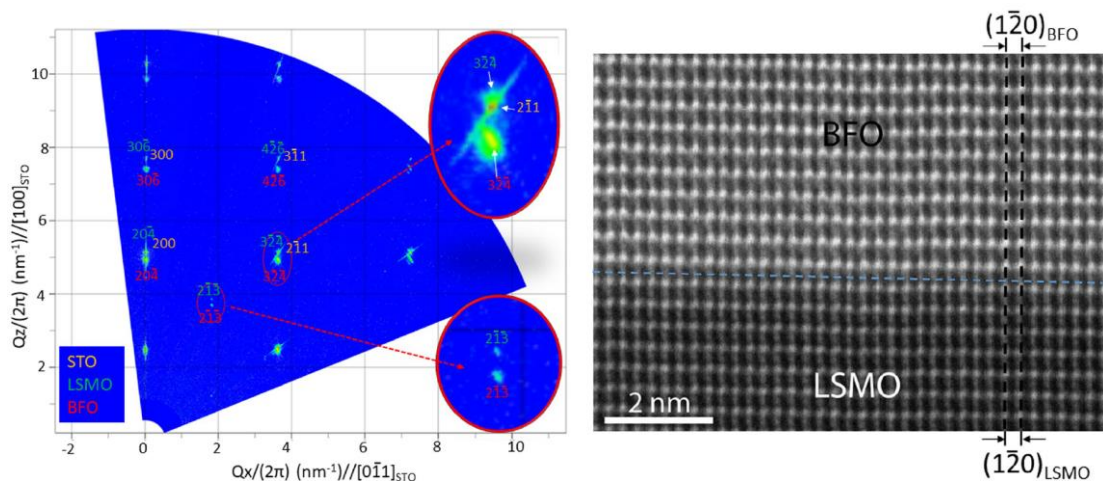


Fig. 1 A XRSM data of the BFO film grown on LSMO/STO substrate, and A cross-sectional HAADF-STEM image at the BFO/LSMO interface along [011] STO zone axis

[Ref]1) I.-T. Bae *et al.*, Jpn. J. Appl. Phys., **57**, 0902A5 (2018). 2) I.-T. Bae *et al.*, Sce. Rep. **9**, 6715 (2019).

[Acknowledgements] This research was partially funded by S3IP at State Univ. NY at Binghamton. The STEM was supported by Tohoku Univ. Nanotech. Platform Pro. (A-18-TU-0013), and the Collabo. Res. Pro. LMS N.H. is grateful for the financial support by KAKENHI (No. 15H03548), and Murata foundation.